













ESD

TVS

TSS

MOV

GDT

PLED

Product data sheet

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General Description

These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

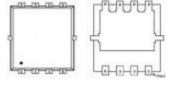
BVDSS	RDSON	ID
-18V	$2.3 \text{m}\Omega$	-80A

Features

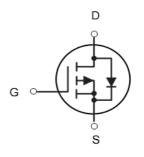
- -18V,-80A, RDS(ON) =2.7 $m\Omega$ @VGS = -10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Networking
- Hand-Held Instruments



DFN5X6-8L



P-Channel MOSFET

Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-18	V
Vgs	Gate-Source Voltage	±12	V
lo.	Drain Current – Continuous (Tc=25°C)	-80	Α
ID	Drain Current – Continuous (Tc=100°C)	-54	Α
Ірм	Drain Current – Pulsed1	-360	Α
Po	Power Dissipation (Tc=25°C)	41.67	W
PD	Power Dissipation – Derate above 25°C	0.33	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter		Max.	Unit
Reja	Thermal Resistance Junction to ambient		62	°C/W
Rejc	Thermal Resistance Junction to Case		3	°C/W

Electrical Characteristics (T_J=25 ℃, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage V _{GS} =0V , I _D =-250uA		-18			V
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 25°C , ID=-1mA		-0.008		V/°C
Ipss	Drain Source Leakage Current	V _{DS} =-20V , V _{GS} =0V , T _J =25°C			-1	uA
IDSS	Drain-Source Leakage Current	VDS=-16V , VGS=0V , TJ=125°C			-30	uA
Igss	Gate-Source Leakage Current	V _G S=±12V , V _D S=0V			±500	nA

On Characteristics

RDS(ON)	RDS(ON) Static Drain-Source On-Resistance	tatic Drain-Source On-Resistance V _{GS} =-4.5V , I _D =-20A		2.3	3.0	mΩ
		V _G S=-2.5V , I _D =-20A	1	3.3	4.5	
V _{GS(th)}	Gate Threshold Voltage	\/\/	-0.4	-0.6	-1.0	V
△Vgs	V _{GS(th)} Temperature Coefficient	Vgs=Vps , Ip =-250uA		-3.44	-	mV/°C
gfs	Forward Transconductance V _{DS} =-10V , Is=-3A			30	-	S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2,3}			149	225	
Qgs	Gate-Source Charge ^{2,3}	VDS=-16V , VGS=-4.5V , ID=-5A		14.4	22	nC
Qgd	Gate-Drain Charge ^{2, 3}		-	42.8	65	
Td(on)	Turn-On Delay Time ^{2, 3}			21.2	42	
Tr	Rise Time ^{2, 3}	V_{DD} =-15 V , V_{GS} =-4.5 V , R_{G} =25 Ω	1	20.6	40	nS
Td(off)	Turn-Off Delay Time ^{2,3}	I _D =-1A		26	52	113
Tf	Fall Time ^{2, 3}		-	400	600	
Ciss	Input Capacitance			12000	16000	
Coss	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , F=1MHz	-	1670	2500	pF
Crss	Reverse Transfer Capacitance			730	1100	
Rg	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz		2.6		Ω

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
ls	Continuous Source Current	Va=Va=0V Force Current			-85	Α
lsм	Pulsed Source Current	V _G =V _D =0V , Force Current			-190	Α
VsD	Diode Forward Voltage	V _G s=0V , I _S =-1A , T _J =25°C			-1	V

Note:

- Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- Essentially independent of operating temperature.

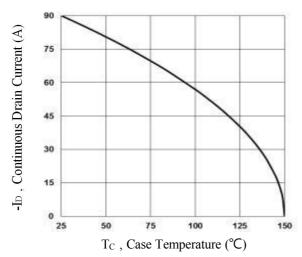


Fig.1 Continuous Drain Current vs. Tc

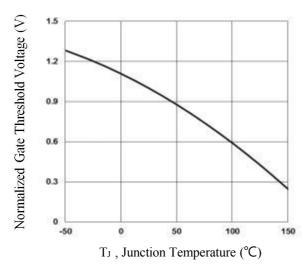


Fig.3 Normalized V_{th} vs. T_J

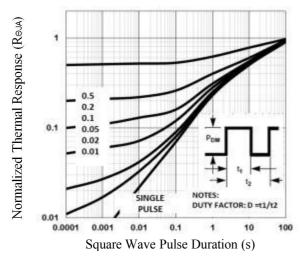


Fig.5 Normalized Transient Response

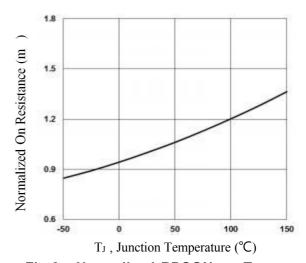


Fig.2 Normalized RDSON vs. T_J

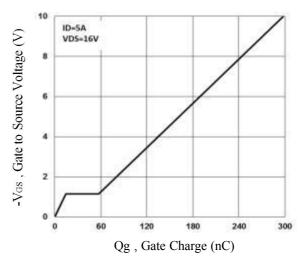


Fig.4 Gate Charge Waveform

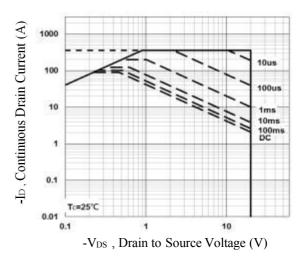
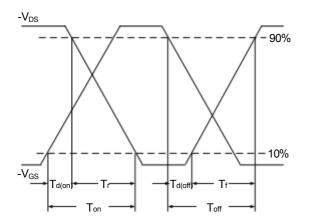


Fig.6 Maximum Safe Operation Area





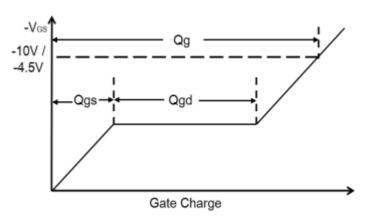


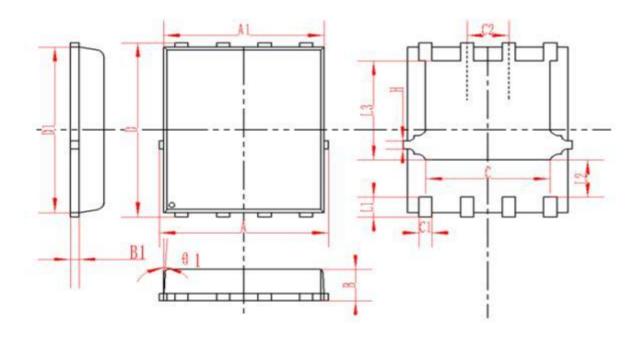
Fig.7 Switching Time Waveform

Fig.8 Gate Charge Waveform





DFN5X6-8L Package Information



SYMBOL		MM			INCH	
STIVIDOL	MIN	NOM	MAX	MIN	NOM	MAX
Α	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1		0.254REF			0.010REF	
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2	1.27TYP				0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010

REEL SPECIFICATION

P/N	PKG	QTY
MSK20P80GNF	DFN5X6-8L	5000



Compiance

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